

EAST SEARCH

12/15/05

L#	Hits	Search String	Databases
S1	2	6.581,191.pn.	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
S2	2	6.618,839.pn.	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
S3	473212	(integrated or digital) adj circuit\$1	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
S4	1329	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describes\$1)) w US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
S5	14	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describes\$1)) s US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
S6	48	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describes\$1)) s US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
S7	7	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describes\$1)) s US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
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S31	2	5,859,993.pn.	
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S33	2	6,353,906.pn.	
S34	2	6,006,022.pn.	
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S37	2	5,937,190.pn.	
S38	1329	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describes\$1)) US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
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S40	630455	((integrated or digital) adj circuit\$1) or (electronic near2 system) US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
S41	486	S40 and (instrumentation near2 circuit\$2) US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
S42	54	S40 and (((integrated or digital) adj circuit\$1) or (electronic near2 system)) with fat US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
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S44	73	S41 and S43	
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S46	9	S45 and ("HDL description")	

S47	25	S41 and ((instrumentation near2 circuit\$2) with configur\$3)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
S48	124	S45 or S46 or S47	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
S49	58	S40 and (embedded near2 test near2 circuitry)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
S50	384	S40 and ((test near2 circuitry) with configur\$5)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
S51	8	S49 and S50	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
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L1	733888	((integrated or digital) adj circuit\$1) or (electronic near2 system)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
L2	557	L1 and (instrumentation near2 circuit\$2)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
L3	75	L1 and ((instrumentation near2 circuit\$2) with (debug\$3 or simulat\$3 or test\$3 or testis\$3 or eUS-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	with fabri US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
L4	69199	L1 and (((integrated or digital) adj circuit\$1) or (electronic near2 system))	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
L5	103	L2 and L4	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
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L9	161	L6 or L7 or L8	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
L10	24	9 and (instrumentation.CLM.)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB																																																																																																																																																
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<p>Results of search set S48:</p> <table border="1"> <thead> <tr> <th>Document Kind</th> <th>Code</th> <th>Title</th> <th>Issue Date</th> <th>Current OR</th> <th>Abstract</th> </tr> </thead> <tbody> <tr> <td>US 20040178938</td> <td>A1</td> <td>Circuit for direct digital delta-sigma conversion of variable electrical capacitance</td> <td>20040916</td> <td>341/143</td> <td></td> </tr> <tr> <td>US 20040154155</td> <td>A1</td> <td>Membrane probing system</td> <td>20040812</td> <td>29/428</td> <td></td> </tr> <tr> <td>US 20040140529</td> <td>A1</td> <td>Increasing an electrical resistance of a resistor by oxidation or nitridization</td> <td>20040722</td> <td>257/537</td> <td></td> </tr> <tr> <td>US 20040093716</td> <td>A1</td> <td>Membrane probing system</td> <td>20040520</td> <td>29/593</td> <td></td> </tr> <tr> <td>US 20040093167</td> <td>A1</td> <td>Analytic detection system with software download capabilities</td> <td>20040513</td> <td>70/223</td> <td></td> </tr> <tr> <td>US 20040078101</td> <td>A1</td> <td>Plant protective instrumentation equipment</td> <td>20040422</td> <td>70/079</td> <td></td> </tr> <tr> <td>US 20040027813</td> <td>A1</td> <td>Manufacturing methods for an electronic assembly with vertically connected capaci</td> <td>20040212</td> <td>361/767</td> <td></td> </tr> <tr> <td>US 20040025122</td> <td>A1</td> <td>Hardware-based HDL code coverage and design analysis</td> <td>20040205</td> <td>71/614</td> <td></td> </tr> <tr> <td>US 20040022038</td> <td>A1</td> <td>Electronic package with back side, cavity mounted capacitors and method of fabric</td> <td>20040205</td> <td>361/763</td> <td></td> </tr> <tr> <td>US 20030192183</td> <td>A1</td> <td>Method for constructing a membrane probe using a depression</td> <td>20031016</td> <td>29/857</td> <td></td> </tr> <tr> <td>US 20030182642</td> <td>A1</td> <td>Hardware debugging in a hardware description language</td> <td>20030925</td> <td>71/614</td> <td></td> </tr> <tr> <td>US 20030168342</td> <td>A1</td> <td>Self-aligned coaxial via capacitors</td> <td>20030911</td> <td>205/122</td> <td></td> </tr> <tr> <td>US 20030155940</td> <td>A1</td> <td>Method for forming cantilever beam probe card and probe card formed</td> <td>20030821</td> <td>324/762</td> <td></td> </tr> <tr> <td>US 20030134441</td> <td>A1</td> <td>Micro probing tip made by micro machine method</td> <td>20030717</td> <td>438/18</td> <td></td> </tr> <tr> <td>US 20030132767</td> <td>A1</td> <td>Membrane probing system</td> <td>20030717</td> <td>324/754</td> <td></td> </tr> <tr> <td>US 20030131325</td> <td>A1</td> <td>Method and user interface for debugging an electronic system</td> <td>20030710</td> <td>71/614</td> <td></td> </tr> <tr> <td>US 20030090278</td> <td>A1</td> <td>Membrane probing system</td> <td>20030515</td> <td>324/754</td> <td></td> </tr> <tr> <td>US 20030069724</td> <td>A1</td> <td>Method and system for debugging an electronic system using instrumentation circu</td> <td>20030410</td> <td>703/16</td> <td></td> </tr> <tr> <td>US 20030036776</td> <td>A1</td> <td>MRI-compatible implantable device</td> <td>20030220</td> <td>60/719</td> <td></td> </tr> <tr> <td>US 20020198674</td> <td>A1</td> <td>Method for testing integrated circuits</td> <td>20021226</td> <td>70/2117</td> <td></td> </tr> <tr> <td>US 20020195700</td> <td>A1</td> <td>Electronic assembly with vertically connected capacitors and manufacturing metho</td> <td>20021226</td> <td>257/700</td> <td></td> </tr> <tr> <td>US 20020191368</td> <td>A1</td> <td>Electronic assembly with laterally connected capacitors and manufacturing method</td> <td>20021219</td> <td>361/306.1</td> <td></td> </tr> <tr> <td>US 20020135388</td> <td>A1</td> <td>Membrane probing system with local contact scrub</td> <td>20020926</td> <td>324/754</td> <td></td> </tr> </tbody> </table>				Document Kind	Code	Title	Issue Date	Current OR	Abstract	US 20040178938	A1	Circuit for direct digital delta-sigma conversion of variable electrical capacitance	20040916	341/143		US 20040154155	A1	Membrane probing system	20040812	29/428		US 20040140529	A1	Increasing an electrical resistance of a resistor by oxidation or nitridization	20040722	257/537		US 20040093716	A1	Membrane probing system	20040520	29/593		US 20040093167	A1	Analytic detection system with software download capabilities	20040513	70/223		US 20040078101	A1	Plant protective instrumentation equipment	20040422	70/079		US 20040027813	A1	Manufacturing methods for an electronic assembly with vertically connected capaci	20040212	361/767		US 20040025122	A1	Hardware-based HDL code coverage and design analysis	20040205	71/614		US 20040022038	A1	Electronic package with back side, cavity mounted capacitors and method of fabric	20040205	361/763		US 20030192183	A1	Method for constructing a membrane probe using a depression	20031016	29/857		US 20030182642	A1	Hardware debugging in a hardware description language	20030925	71/614		US 20030168342	A1	Self-aligned coaxial via 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US 5793218 A	Generic interface test adapter	19980811 324/754
US 5788927 A	Unified fluid circuit assembly for a clinical hematology instrument	19980804 422/63
US 5772963 A	Analytical instrument having a control area network and distributed logic nodes	19980630 422/67
US 5745308 A	Methods and apparatus for an optical illuminator assembly and its alignment	19980428 359/818
US 5719667 A	Apparatus for filtering a laser beam in an analytical instrument	19980217 356/73
US 5701082 A	Probe for sensing modulated signals and method of using same	19971223 324/628
US 5691486 A	Apparatus and methods for selecting a variable number of test sample aliquots to n	19971125 73/63.73
US 5689192 A	Method for simulating a controlled voltage for testing circuits for electromagnetic su	19971118 324/627
US 5648926 A	Silicon neuron	19970715 708/801
US 5585765 A	Low power RC oscillator using a low voltage bias circuit	19961217 331/111
US 5583739 A	Capacitor fabricated on a substrate containing electronic circuitry	19961210 361/313
US 5570067 A	Micropower RC oscillator having hysteresis produced by switching current sources	19961029 331/111
US 5522715 A	Apparatus for low cost electromagnetic field susceptibility testing	19960903 324/627
US 5472900 A	Capacitor fabricated on a substrate containing electronic circuitry	19951205 438/396
US 5449903 A	Methods of fabricating integrated, aligned tunneling tip pairs	19950912 250/306
US 5416429 A	Probe assembly for testing integrated circuits	19950516 324/762
US 5414345 A	Apparatus and method for low cost electromagnetic field susceptibility testing	19950509 324/72.5
US 5311486 A	Timing generation in an automatic electrical test system	19940510 368/10
US 5335187 A	Methods of fabricating integrated, aligned tunneling tip pairs	19930810 250/306
US 5103378 A	Hinged interlocking receiver for mainframe card cage	19920407 361/802
US 4907230 A	Apparatus and method for testing printed circuit boards and their components	19900306 714/724
US 4856530 A	Catheter identifier and method	19890815 600/505
US 4785175 A	Inspection of buried pipelines	19881115 250/360.1
US 4675594 A	Voltage-to-current converter	19870623 323/317
US 4579600 A	Method of making zero temperature coefficient of resistance resistors	19860401 438/385
US 4407789 A	Magnetic heading simulator	19830823 703/13
US 4395677 A	Hall Effect tester for heated window grids	19830726 324/117H
US 4305319 A	Modular drum generator	19811215 84/611
US 4282515 A	Analog to digital encoding system with an encoder structure incorporating instrume	19810804 341/118
US 4262248 A	System for servicing process instrumentation	19810414 324/72.5
US 4232271 A	Instrumentation amplifier with extended common mode range	19801104 330/258
US 4135423 A	Automatic rhythm generator	19790123 84/635
US 3918751 A	TESTING APPARATUS FOR ELASTOMERS	19740625 374/46
US 3854555 A	COORDINATE CONVERSION FOR THE TESTING OF PRINTED CIRCUIT BOAF	19720404 439/65
US 3836450 A	DIGITAL MOS FET CHARACTERISTIC TESTER	19720118 324/769
US 3829685 A	PRERECORDED ELECTRONIC TAPE CONTROLLED CIRCUIT TESTING SYST	19711221 324/73.1
JP 2003287587 A	PLANT PROTECTION INSTRUMENTATION DEVICE	20031010
US 66118639 B	Fabricated integrated circuit debugging method e.g. for application specific integrat	20030909 55
US 20030131325 A	Fabricated integrated circuits debugging method for electronic system designs, inv	20030710 96
US 20030069724 A	Computer system debugging method involves translating debug data received from	20030410 96
US 6075234 A	Integrated circuit test instrumentation triggering method involves applying trigger si.	20000613
EP 510101 A	Mixed analogue and digital integrated circuit for physiological instrumentation - has	19950419
DD 266433 A	Interference pulse detection circuit for instrumentation testing - has input or-gate fo	19870603

Interference checking
done

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L#	Hits	Search String	Databases
L1	733888	((integrated or digital) adj circuit\$1) or (electronic near2 system)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L2	557	L1 and (instrumentation near2 circuit\$2)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L3	75	L1 and ((instrumentation near2 circuit\$2) with (debug\$3 or test\$3 or simulat\$3 or e US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
L4	69199	L1 and (((integrated or digital) adj circuit\$1) or (electronic near2 system)) with fabr US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB	
L5	1033	L2 and L4	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L6	137	L3 or L5	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L7	16	L6 and ("HDL description")	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L8	28	L2 and ((instrumentation near2 circuit\$2) with config\$3)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L9	161	L6 or L7 or L8	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L10	24	9 and (instrumentation.CLM.)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L12	11	10 and ("HDL description".CLM.)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L13	3	11 and 12	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L11	5	10 and (configuration.CLM.)	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L14	24	10 or 11 or 12 or 13	US-PGPUB; USPAT; EPO; JPO; DERVENT; IBM_TDB
L15	17594	L1 and (((integrated or digital) adj circuit\$1) or (electronic near2 system)) with fabr US-PGPUB	US-PGPUB
L16	144	L1 and (instrumentation near2 circuit\$2)	US-PGPUB
L17	43	15 and 16	US-PGPUB
L18	8	17 and (instrumentation.CLM.)	US-PGPUB
L19	6	17 and ("HDL description".CLM.)	US-PGPUB
L21	1	17 and (configuration.CLM.)	US-PGPUB
L22	8	18 or 19 or 21	US-PGPUB

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EAST SEARCH

12/15/05

Results of search set \$48:	Document Kind Codes Title	Issue Date	Current OR	Abstract
US 20040178938 A1 Circuit for direct digital delta-sigma conversion of variable electrical capacitance		20040916	34/1/143	
US 20040154155 A1 Membrane probing system		20040812	29/14/28	
US 20040140529 A1 Increasing an electrical resistance of a resistor by oxidation or nitridization		20040722	25/7/537	
US 20040093716 A1 Membrane probing system		20040520	29/5/93	
US 20040093167 A1 Analyte detection system with software download capabilities		20040513	70/2/23	
US 20040078101 A1 Plant protective instrumentation equipment		20040422	70/7/79	
US 20040027813 A1 Manufacturing methods for an electronic assembly with vertically connected capac		20040212	36/1/767	
US 20040025122 A1 Hardware-based HDL code coverage and design analysis		20040205	71/6/4	
US 20040022038 A1 Electronic package with back side, cavity mounted capacitors and method of fabric		20040205	36/1/763	
US 20030192183 A1 Method for constructing a membrane probe using a depression		20031016	29/8/57	
US 20030182642 A1 Hardware debugging in a hardware description language		20030925	71/6/4	
US 20030168342 A1 Self-aligned coaxial via capacitors		20030911	20/5/122	
US 20030155940 A1 Method for forming cantilever beam probe card and probe card formed		20030821	32/4/762	

US 20030134441 A1	Micro probing tip made by micro machine method	20030717 438/18
US 20030132767 A1	Membrane probing system	20030717 324/754
US 20030131325 A1	Method and user interface for debugging an electronic system	20030710 716/14
US 20030090278 A1	Membrane probing system	20030515 324/754
US 20030069724 A1	Method and system for debugging an electronic system using instrumentation circa	20030410 703/16
US 20030036776 A1	MRI-compatible implantable device	20030220 607/9
US 20020198674 A1	Method for testing integrated circuits	20021226 702/117
US 20020195700 A1	Electronic assembly with vertically connected capacitors and manufacturing method	20021226 257/700
US 20020191368 A1	Electronic assembly with laterally connected capacitors and manufacturing method	20021219 361/306.1
US 20020135388 A1	Membrane probing system with local contact scrub	20020926 324/754
US 20020134685 A1	SELF ALIGN COAXIAL VIA CAPACITORS	20020926 205/125
US 20020134581 A1	Hybrid capacitor, circuit, and system	20020926 174/260
US 20020132533 A1	Discrete device socket and method of fabrication therefor	20020919 439/862
US 20020113651 A1	Instrumentation amplifier	20020822 330/258
US 20020085334 A1	Multiple tier array capacitor and methods of fabrication therefor	20020704 361/301.4
US 20020075630 A1	Capacitor with extended surface lands and method of fabrication therefor	20020620 361/308.1
US 20020066858 A1	Glucose monitoring instrument having network connectivity	20020606 600/316
US 20020030549 A1	Membrane probing system	200111018 324/758
US 2001010468 A1	Membrane probing system	20010802 324/715
US 20010098785 A1	Method of fabricating a supply decoupling capacitor	20010726 438/210
US 2001009061 A1	Membrane probing system	20010726 29/593
US 6797528 B2	Micro probing tip made by micro machine method	20040928 438/14
US 6757632 B2	Method and apparatus for testing integrated circuits using a synchronization signal	20040629 702/117
US 6730984 B1	Increasing an electrical resistance of a resistor by oxidation or nitridization	20040504 257/537
US 6713860 B2	Electronic assembly and system with vertically connected capacitors	20040330 257/700
US 6708386 B2	Method for probing an electrical device having a layer of oxide thereon	20040323 29/593
US 6672912 B2	Discrete device socket and method of fabrication therefor	20040106 439/862
US 6651325 B2	Method for forming cantilever beam probe card and probe card formed	20031125 29/846
US 6645142 B2	Glucose monitoring instrument having network connectivity	20031111 600/300
US 6636416 B2	Electronic assembly with laterally connected capacitors and manufacturing method	20031021 361/306.1
US 6625557 B1	Mixed signal device under test board interface	20030923 702/117
US 6618839 B1	Method and system for providing an electronic system design with enhanced debug	20030909 716/4
US 6590294 B1	Device for bump probing and method of fabrication	20030708 257/781
US 6581191 B1	Hardware debugging in a hardware description language	20030617 716/4
US 6578264 B1	Method for constructing a membrane probe using a depression	20030617 29/874
US 6565730 B2	Self-aligned coaxial via capacitors	20030520 205/122
US 6558503 B2	Instrumentation amplifier and method for obtaining high common mode rejection	20030325 330/9
US 6532143 B2	Multiple tier array capacitor	20030311 361/301.4
US 6483692 B2	Capacitor with extended surface lands and method of fabrication therefor	20021119 361/308.1
US 6452776 B1	Capacitor with defect isolation and bypass	20020917 361/303
US 6446317 B1	Hybrid capacitor and method of fabrication therefor	20020910 29/25.42
US 6337584 B1	Membrane probing system with local contact scrub	20020820 324/754
US 6407929 B1	Electronic package having embedded capacitors and method of fabrication therefo	20020618 361/763
US 6307387 B1	Membrane probing system with local contact scrub	20011023 324/754
US 6256882 B1	Membrane probing system	20010710 29/874
US 6204715 B1	Signal amplifying circuit	20010320 327/309
US 6195629 B1	Method and system for selectively disabling simulation model instrumentation	20010227 703/17
US 6163724 A	Microprocessor capture detection circuit and method	20001219 607/28
US 6144881 A	Capture detection circuit for pulses and physiologic signals	20001107 607/28

US 6134473 A	Microprocessor capture detection circuit and method	200001017 607/28
US 6122053 A	Apparatus for measuring particle fallout on a surface using a telltale plate	20000919 356/338
US 6075234 A	Non-contact method and apparatus to obtain a timing signal from internal integrate	20000613 250/207
US 6042249 A	Illuminator optical assembly for an analytical instrument and methods of alignment	20000328 362/259
US 6027980 A	Method of forming a decoupling capacitor	20000222 438/396
US 5991324 A	Reliable, modular, production quality narrow-band KRF excimer laser	19991123 372/57
US 5973910 A	Decoupling capacitor in an integrated circuit	19991026 361/313
US 5973842 A	Method and apparatus for an optical illuminator assembly and its alignment	19991026 359/619
US 5954756 A	Microprocessor capture detection circuit and method	19990921 607/28
US 5953681 A	Autonomous node for a test instrument system having a distributed logic nodal arc	19990914 702/31
US 5936986 A	Methods and apparatus for driving a laser diode	19990810 372/38.02
US 5934885 A	Reagent pump assembly	19990810 417/392
US 5914613 A	Membrane probing system with local contact scrub	19990622 324/754
US 5908599 A	Heated reaction chamber in a unified fluid circuit of a hematology diagnostic instru	19990601 422/50
US 5883378 A	Apparatus and methods for transmitting electrical signals indicative of optical intere	19990316 250/214A
US 5873898 A	Microprocessor capture detection circuit and method	19990223 607/28
US 5872627 A	Method and apparatus for detecting scattered light in an analytical instrument	19990216 356/338
US 5871512 A	Microprocessor capture detection circuit and method	19990216 607/28
US 5844685 A	Reference laser beam sampling apparatus	19981201 356/433
US 5793218 A	Generic interface test adapter	19980811 324/754
US 5788927 A	Unified fluid circuit assembly for a clinical hematology instrument	19980804 422/63
US 5772963 A	Analytical instrument having a control area network and distributed logic nodes	19980630 422/67
US 5745308 A	Methods and apparatus for an optical illuminator assembly and its alignment	19980428 359/318
US 5719667 A	Apparatus for filtering a laser beam in an analytical instrument	19980217 356/73
US 5701082 A	Probe for sensing modulated signals and method of using same	19971223 324/628
US 5691486 A	Apparatus and methods for selecting a variable number of test sample aliquots to t	19971125 73/863.73
US 5689192 A	Method for simulating a controlled voltage for testing circuits for electromagnetic si	19971118 324/627
US 5648926 A	Silicon neuron	19970715 708/801
US 5585765 A	Low power RC oscillator using a low voltage bias circuit	19961217 331/111
US 5583739 A	Capacitor fabricated on a substrate containing electronic circuitry	19961210 361/313
US 5570067 A	Micropower RC oscillator having hysteresis produced by switching current sources	19961029 331/111
US 5552715 A	Apparatus for low cost electromagnetic field susceptibility testing	19960903 324/627
US 5472900 A	Capacitor fabricated on a substrate containing electronic circuitry	19951205 438/396
US 5449903 A	Methods of fabricating integrated, aligned tunneling tip pairs	19950912 250/306
US 5416429 A	Probe assembly for testing integrated circuits	19950516 324/762
US 5414345 A	Apparatus and method for low cost electromagnetic field susceptibility testing	19950509 324/72.5
US 5311486 A	Timing generation in an automatic electrical test system	19940510 368/10
US 5235187 A	Methods of fabricating integrated, aligned tunneling tip pairs	19930810 250/306
US 5103378 A	Hinged interlocking receiver for mainframe card cage	19920407 361/802
US 4907230 A	Apparatus and method for testing printed circuit boards and their components	19900306 714/724
US 4856530 A	Catheter identifier and method	19890815 600/505
US 4785175 A	Inspection of buried pipelines	19881115 250/360.1
US 4675594 A	Voltage-to-current converter	19870623 323/317
US 4579600 A	Method of making zero temperature coefficient of resistance resistors	19860401 438/385
US 440789 A	Magnetic heading simulator	19830823 703/13
US 4395677 A	Hall Effect tester for heated window grids	19830726 324/117H
US 4305319 A	Modular drum generator	19811215 84/611
US 4282515 A	Analog to digital encoding system with an encoder structure incorporating instrume	19810804 341/118
US 4262248 A	System for servicing process instrumentation	19810414 324/72.5

US 4232271 A	Instrumentation amplifier with extended common mode range	19801104 330/258
US 4135423 A	Automatic rhythm generator	19790123 84/635
US 3818751 A	TESTING APPARATUS FOR ELASTOMERS	19740625 374/46
US 3654585 A	COORDINATE CONVERSION FOR THE TESTING OF PRINTED CIRCUIT BOAR	19720404 439/65
US 3636450 A	DIGITAL MOS FET CHARACTERISTIC TESTER	19720118 324/789
US 329695 A	PRERECORDED ELECTRONIC TAPE CONTROLLED CIRCUIT TESTING SYSTE	19711221 324/73.1
JP 2003287587 A	PLANT PROTECTION INSTRUMENTATION DEVICE	20031010
US 6618839 B	Fabricated integrated circuit debugging method e.g. for application specific integral	20030909 55
US 20030131325 A	Fabricated integrated circuits debugging method for electronic system designs, inv	20030710 96
US 20030069724 A	Computer system debugging method involves translating debug data received from	20030410 96
US 6075234 A	Integrated circuit test instrumentation triggering method involves applying trigger si	20000613
EP 570101 A	Mixed analogue and digital integrated circuit for physiological instrumentation - has	19950419
DD 246433 A	Interference pulse detection circuit for instrumentation testing - has input or gate fc	19870603

Results of search set L14:

Document Kind	Codes	Title	Issue Date	Current OR	Abstract
US 20050193280 A1		Design instrumentation circuitry	20050901 714/47		
US 20050149313 A1		Method and system for selective compilation of instrumentation entities into a simu	20050707 703/22		
US 20050125754 A1		Hardware debugging in a hardware description language	20050609 716/5		
US 20050105281 A1		ELECTRONIC MODULE WITH REMOVABLE CIRCUITRY AND METHOD THERE	20050519 361/796		
US 20050010880 A1		Method and user interface for debugging an electronic system	20050113 716/4		
US 20040078101 A1		Plant protective instrumentation equipment	20040422 700/79		
US 20040025122 A1		Hardware-based HDL code coverage and design analysis	20040205 716/4		
US 20030182642 A1		Hardware debugging in a hardware description language	20030925 716/4		
US 20030131325 A1		Method and user interface for debugging an electronic system	20030710 716/4		
US 20030069724 A1		Method and system for debugging an electronic system using instrumentation circi	20030410 703/16		
US 20020113651 A1		Instrumentation amplifier	20020822 330/258		
US 6931572 B1		Design instrumentation circuitry	20050816 714/34		
US 6904577 B2		Hardware debugging in a hardware description language	20050607 716/4		
US 6823497 B2		Method and user interface for debugging an electronic system	20041123 716/4		
US 6618839 B1		Method and system for providing an electronic system design with enhanced debu	20030909 716/4		
US 6581191 B1		Hardware debugging in a hardware description language	20030617 716/4		
US 6538503 B2		Instrumentation amplifier and method for obtaining high common mode rejection	20030325 330/9		
US 6195629 B1		Method and system for selectively disabling simulation model instrumentation	20010227 703/17		
US 6075234 A		Non-contact method and apparatus to obtain a timing signal from internal integrate	20000613 250/207		
US 5991324 A		Reliable, modular, production quality narrow-band KRF excimer laser	19991123 372/57		
US 4856530 A		Catheter identifier and method	19890815 600/505		
US 4262248 A		System for servicing process instrumentation	19810414 324/72.5		
US 4232271 A		Instrumentation amplifier with extended common mode range	19801104 330/258		
US 4135423 A		Automatic rhythm generator	19790123 84/635		